

PRINCIPLES OF MODERN RADAR: VOLUME 3

JAMES A. SCHEER AND WILLIAM L. MELVIN

The third and final volume in the *Principles of Modern Radar* series presents specific real-world applications of radar systems, drawing upon previous editions by combining underlying basic principles with advanced radar techniques.

- Provides in-depth discussions of the most important application areas in current radar practice.
- Includes concise descriptions of the purposes, principal issues and radar methods found in a wide variety of current radar types.
- Types of radar considered include; low-power continuous wave (CW) radar, weather radar and military applications.
- Each chapter is authored by experts in the field who are active in research and teaching radar practitioners in professional courses.

READERSHIP

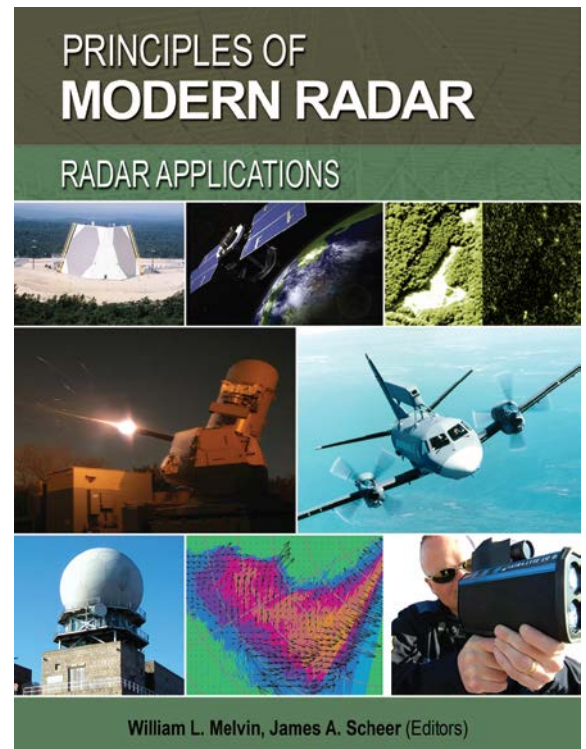
This edition will serve as a self-contained reference for those aiming to become experts in an advanced technology or application area. Primarily aimed at radar practitioners within military or government and will also be useful for some advanced graduate students.

AUTHOR INFORMATION

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PREVIOUS EDITIONS

- Principles of Modern Radar: Advanced Techniques (2012) ISBN: 978-1-89112-153-1
- Principles of Modern Radar: basic principles (2010) ISBN: 978-1-89112-152-4



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